IGBT - Field Stop, Trench, Soft Fast Recovery Diode

650 V, 160 A

FGY160T65SPD-F085

Benefits

- Very Low Conduction and Switching Losses for a High Efficiency Operation in Various Applications
- Rugged Transient Reliability
- Outstanding Parallel Operation Performance with Balance Current Sharing
- Low EMI

Features

- AEC-Q101 Qualified and PPAP Capable
- Very Low Saturation Voltage: V_{CE(sat)} = 1.6 V (Typ.) @ I_C = 160 A
- Maximum Junction Temperature: $T_J = 175^{\circ}C$
- Positive Temperature Co-Efficient
- Tight Parameter Distribution
- High Input Impedance
- 100% of the Parts are Dynamically Tested
- Short circuit ruggedness > 6 µs @ 25°C
- Copacked with Soft, Fast Recovery Extremefast Diode
- This Device is Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

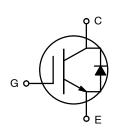
Applications

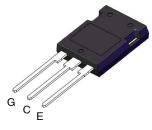
- Traction Inverter for HEV/EV
- Auxiliary DC/AC Converter
- Motor Drives
- Other Power-Train Applications Requiring High Power Switch



ON Semiconductor®

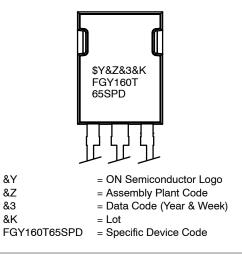
www.onsemi.com





TO-247-3LD CASE 340CU

MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 2 of this data sheet.

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Ratings	Unit
V _{CES}	Collector to Emitter Voltage	650	V
V _{GES}	Gate to Emitter Voltage	±20	V
	Transient Gate to Emitter Voltage	±30	V
Ι _C	Collector Current @ T _C = 25°C (Note 1)	240	А
	Collector Current @ T _C = 100°C	220	А
I _{Nominal}	Nominal Current	160	А
I _{CM}	Pulsed Collector Current	480	А
I _{FM}	Diode Forward Current @ $T_C = 25^{\circ}C$ (Note 1)	240	А
	Diode Forward Current @ T _C = 100°C	188	А
PD	Maximum Power Dissipation @ $T_C = 25^{\circ}C$	882	W
	Maximum Power Dissipation @ $T_C = 100^{\circ}C$	441	W
SCWT	Short Circuit Withstand Time @ $T_C = 25^{\circ}C$	6	μs
$\Delta V / \Delta t$	Voltage Transient Ruggedness (Note 2)	10	V/ns
TJ	Operating Junction Temperature	–55 to +175	°C
T _{stg}	Storage Temperature Range	–55 to +175	°C
TL	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
1. Limited to bondwire.
2. V_{CC} = 400 V, V_{GE} = 15 V, I_{CE} = 480 A, Inductive load.

THERMAL CHARACTERISTICS

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$ (IGBT)	Thermal Resistance, Junction to Case	-	0.17	°C/W
$R_{\theta JC}$ (Diode)	Thermal Resistance, Junction to Case	-	0.32	°C/W
$R_{\theta JA}$	R _{0JA} Thermal Resistance, Junction to Ambient		40	°C/W

PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Packing Type	Qty per Tube
FGY160T65SPD	FGY160T65SPD-F085	TP-247-3LD	Tube	30 ea

ELECTRICAL CHARACTERISTICS OF THE IGBT (T_J = 25° C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit	
OFF CHARACTERISTICS							
BV _{CES}	Collector to Emitter Breakdown Voltage	V _{GE} = 0 V, I _C = 1 mA	650	-	-	V	
$\Delta { m BV}_{ m CES}/ \Delta { m T}_{ m J}$	Temperature Coefficient of Breakdown Voltage	V _{GE} = 0 V, I _C = 1 mA	-	0.6	-	V/°C	
I _{CES}	Collector Cut-Off Current	$V_{CE} = V_{CES}, V_{GE} = 0 V$	-	-	40	μΑ	
I _{GES}	G-E Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0 V$	-	-	±250	nA	

ON CHARACTERISTICS

V _{GE(th)}	G-E Threshold Voltage	I_{C} = 160 mA, V_{CE} = V_{GE}	4.3	5.3	6.3	V
V _{CE(sat)}	Collector to Emitter Saturation Voltage	I_{C} = 160 A, V_{GE} = 15 V	-	1.6	2.05	V
		I _C = 160 A, V _{GE} = 15 V, T _J = 175°C	-	2.15	-	V

ELECTRICAL CHARACTERISTICS OF THE IGBT (T_J = 25°C unless otherwise noted) (continued)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
DYNAMIC CH	IARACTERISTICS					
Cies	Input Capacitance	$V_{CE} = 30 V, V_{GE} = 0 V,$	_	6710	-	pF
C _{oes}	Output Capacitance	f = 1 MHz	-	450	-	pF
C _{res}	Reverse Transfer Capacitance		-	55	-	pF
R _G	Internal Gate Resistance	f = 1 MHz	_	3	_	Ω
SWITCHING (CHARACTERISTICS					
T _{d(on)}	Turn-On Delay Time	$V_{CC} = 400 \text{ V, } I_C = 160 \text{ A,} \\ R_G = 5 \Omega, V_{GE} = 15 \text{ V,} \\ \text{Inductive Load, } T_J = 25^{\circ}\text{C}$	-	53	-	ns
Tr	Rise Time		-	197	-	ns
T _{d(off)}	Turn-Off Delay Time		-	98	-	ns
Τ _f	Fall Time		-	141	-	ns
Eon	Turn-On Switching Loss		-	12.4	-	mJ
E _{off}	Turn-Off Switching Loss		-	5.7	-	mJ
E _{ts}	Total Switching Loss		-	18.1	-	mJ
T _{d(on)}	Turn-On Delay Time	$V_{CC} = 400 \text{ V}, \text{ I}_{C} = 160 \text{ A},$	-	52	-	ns
Tr	Rise Time	$R_G = 5 \Omega$, $V_{GE} = 15 V$, Inductive Load, $T_J = 175^{\circ}C$	-	236	-	ns
T _{d(off)}	Turn-Off Delay Time		-	104	-	ns
Τ _f	Fall Time		-	204	-	ns
Eon	Turn-On Switching Loss		-	21	-	mJ
E _{off}	Turn-Off Switching Loss		_	8.5	-	mJ
E _{ts}	Total Switching Loss		_	29.5	-	mJ
Qg	Total Gate Charge	$V_{CE} = 400 \text{ V}, I_{C} = 160 \text{ A},$	_	163	245	nC
0	Gate to Emitter Charge	V _{GE} = 15 V	_	50	_	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

50

49

_

_

nC

nC

ELECTRICAL CHARACTERISTICS OF THE DIODE (T_J = 25° C unless otherwise noted)

Gate to Emitter Charge

Gate to Collector Charge

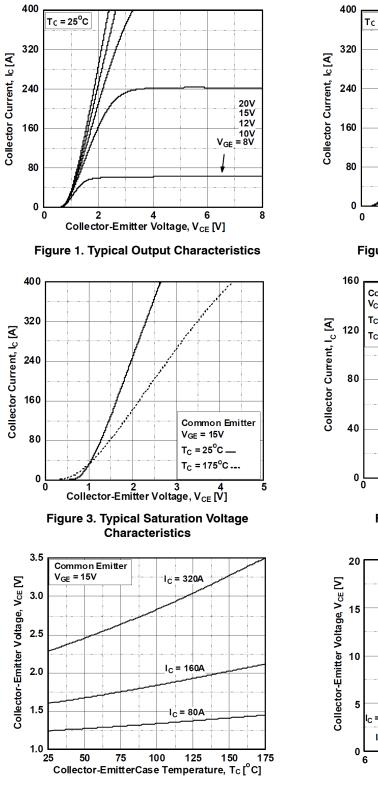
Qge

Q_{gc}

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V_{FM}	Diode Forward Voltage	I _F = 160 A	$T_J = 25^{\circ}C$	-	1.4	1.7	V
			T _J = 175°C	-	1.35	-	
E _{rec}	E _{rec} Reverse Recovery Energy V _{CE} =		$T_J = 25^{\circ}C$	-	598	-	μJ
		$\Delta I_{F}/\Delta t = 1000 \text{ A}/\mu \text{s}$	T _J = 175°C	-	4000	-	
T _{rr}		very	$T_J = 25^{\circ}C$	-	132	-	ns
	Time		T _J = 175°C	-	245	-	
Q _{rr}	Diode Reverse Recovery		$T_J = 25^{\circ}C$	-	3.3	_	μC
	Charge		T _J = 175°C	-	12.5	-	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL PERFORMANCE CHARACTERISTICS





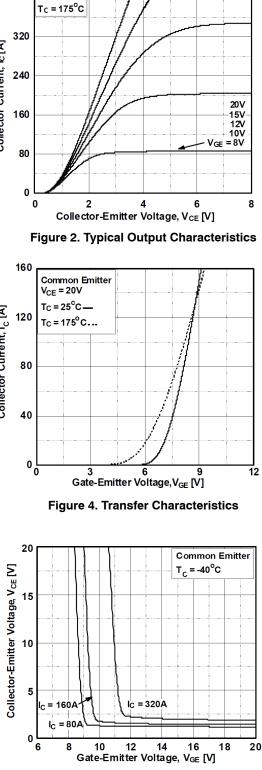
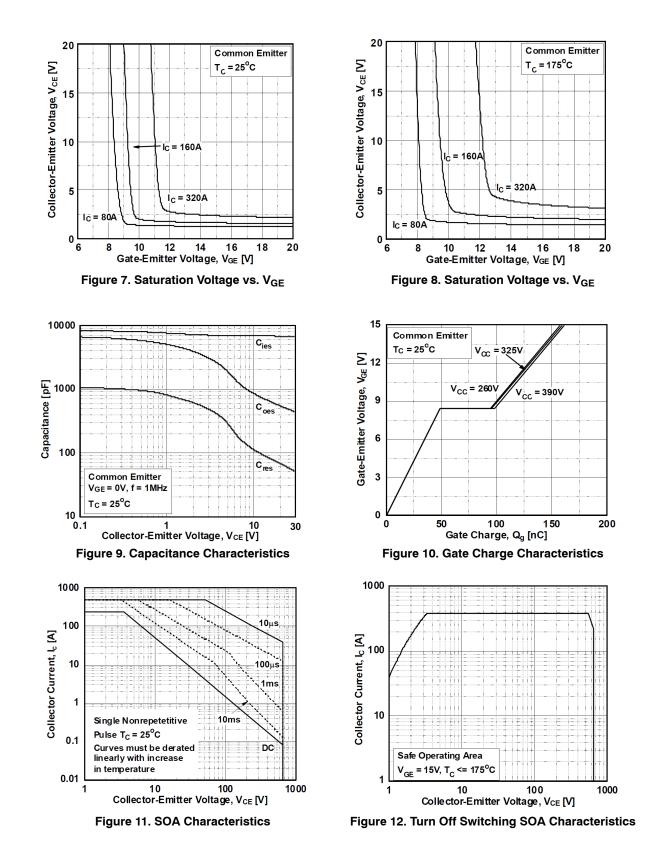


Figure 6. Saturation Voltage vs. V_{GE}



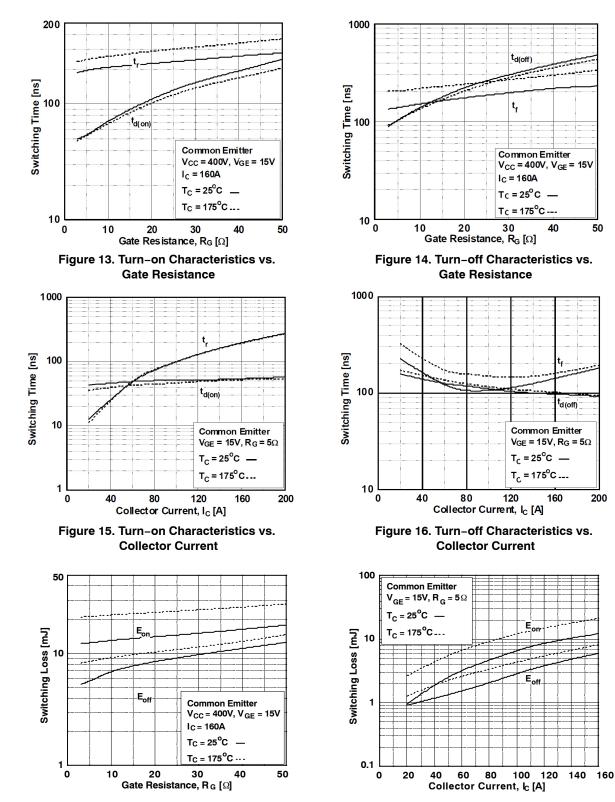
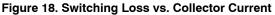
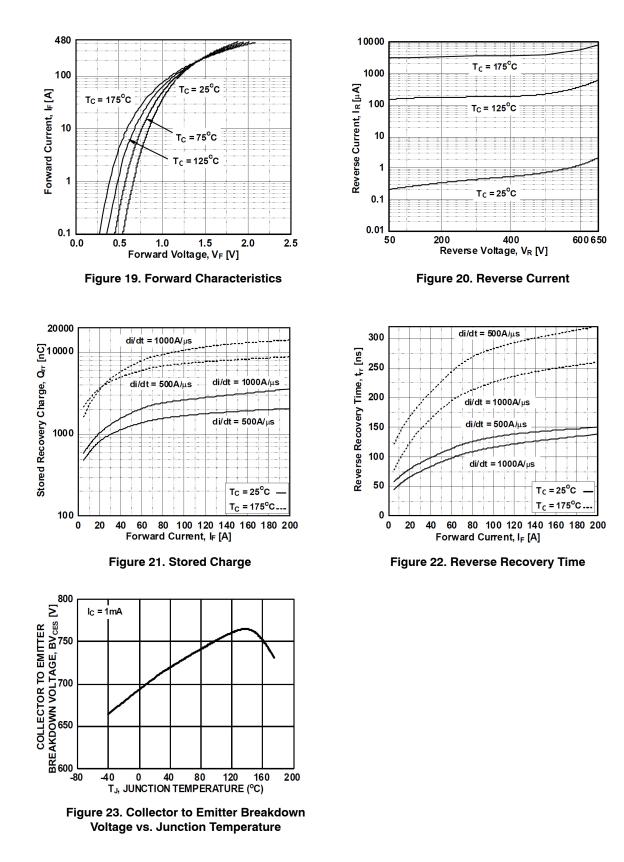


Figure 17. Switching Loss vs. Gate Resistance





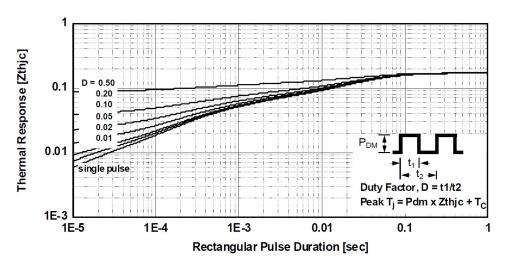


Figure 24. Transient Thermal Impedance of IGBT

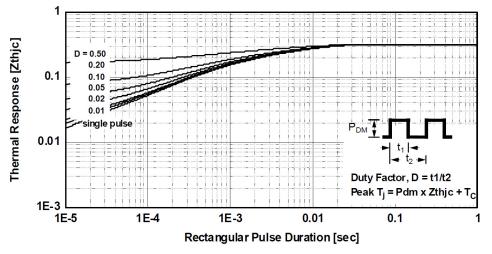
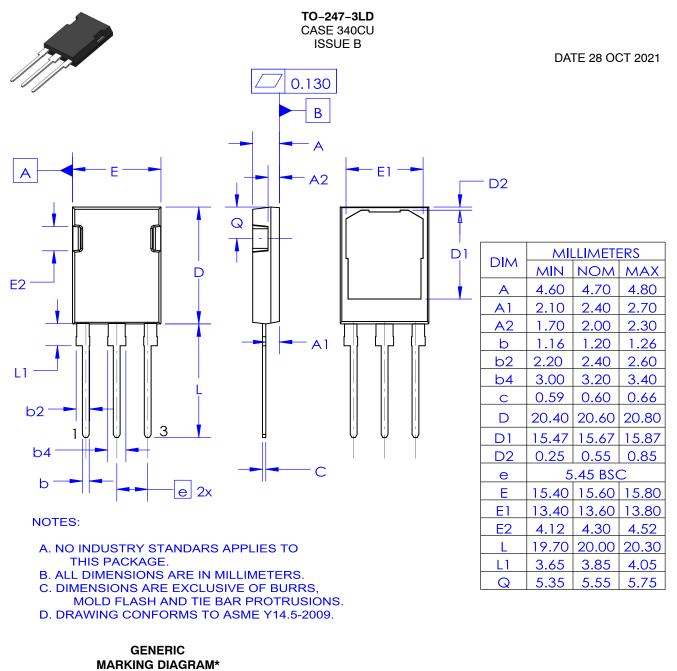


Figure 25. Transient Thermal Impedance of Diode

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С AYWWZZ XXXXXXXXX

XXXXXXXXXX

XXXX = Specific Device Code = Assembly Site Code = Year ww = Work Week

Α

Υ

ZZ

= Assembly Lot Code

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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DESCRIPTION:	TO-247-3LD		PAGE 1 OF 1

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